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PATENT
Atty Docket:P70853US0

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Confirmation No.: 8295

DOBSCHAL et al.

Serial No.: 10/554,048

Group Art Unit: Not Yet Assigned

Filed: October 24, 2005

Examiner: Not Yet Assigned

For: APPARATUS FOR INSPECTING OBJECTS, ESPECIALLY MASKS IN
MICROLITHOGRAPHY

**INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR 1.97**

MAIL STOP AMENDMENT

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

As a continuing means of complying with the duty of disclosure under 37 CFR §1.56, and in accordance with 37 CFR §§1.97 and 1.98, Applicant through his undersigned attorney, submits this Information Disclosure Statement for the Examiner's consideration. The patents, publications or other information submitted herewith are listed on the attached Form PTO-1449. In accordance with 37 CFR §1.98(a)(2) only a copy of each foreign patent document and non-patent literature document listed on the attached Form PTO-1449 is submitted herewith.

In accordance with 37 CFR §1.97(b) this Information Disclosure Statement is being submitted before the mailing of the first Office Action on the merits and therefore, no fee is due.

The patents and publications AA-AB, AH and AK listed on Form PTO-1449 were cited in an International Search Report in counterpart Patent Application No. PCT/EP2004/004161. A copy of the Search Report is enclosed.

Serial No.: 10/554,048
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Documents AD, AI and AJ were cited in an Office Action in a counterpart German Application No. DE 103 18 560.7. A copy of the Office Action is enclosed.

Only the first page of each foreign patent is being submitted as each document has an English language equivalent. The English language documents and their foreign equivalent are as follows: Document AC = AH and AI; Document AE = AJ; Document AF = AG.

Document AC is cited in the instant specification on page 3.

It is respectfully requested that the Examiner initial and return a copy of the enclosed Form PTO-1449, and to similarly indicate in the official file wrapper of this patent application that the attached documents have been considered. If the Examiner has any questions or wishes to discuss this application, the Examiner is invited to telephone the undersigned representative at the number set forth below.

Respectfully submitted,

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Form PTO-1449

INFORMATION DISCLOSURE STATEMENT

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Application No.:	10/554,048
Filing Date:	October 24, 2005
Inventor:	DOBSCHAL et al.
Art Unit:	Not Yet Assigned
Examiner:	Not Yet Assigned

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number	Publication Date	Name of Patentee or Applicant	Relevant Pages, Cols, Lines, Figs.
	AA	US- 5,498,923 A	3/12/96	LA FONTAINE et al.	
	AB	US- 3,917,950 A	11/4/75	CARLSON	
	AC	US- 6,492,644	12/10/02	STAIB	
	AD	US- 2003/0011896 A1	1/16/03	SHIRAISHI	
	AE	US- 2001/0012099 A1	8/9/01	KUMAGAI	
	AF	US- 2004/0174607 A1	9/9/04	BRUNNER et al.	

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Country Code + Number	Publication Date	Name of Patentee or Applicant	Relevant Pages, Cols, Lines, Figs.	Translation
	AG	DE 10130212 A1	1/2/03	CARL ZEISS JENA GMBH		SEE AF
	AH	EP 1 063 676 A	12/27/00	STAIB INSTR GMBH		SEE AC
	AI	DE 19929185 A1	6/25/99	STAIB INSTR GMBH		SEE AC
	AJ	DE 10063239 A1	12/19/00	NIKON CORP		SEE AE

NON-PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	Include name of author in CAPS; title of article; title of book, magazine, journal etc.; date; page(s); volume/issue number(s); publisher; city and/country where published.
	AK	IMADA S ET AL; "Epitaxial Growth of Ferroelectric YMnO ₃ thin films on Si (111) Substrates by Molecular Beam Epitaxy"; Japanese Journal of Applied Physics; Publication Office Japanese Journal of Applied Physics; December 1998; pgs. 6497-6501; vol. 37 no. 12A Part 1; Tokyo.

Examiner Signature	Date Considered
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.